

INFORMATION DISCLOSURE  
CITATION

ATTY. DOCKET NO.

SERIAL NO.

4105-18

10/615,600

APPLICANT

CHO et al.

FILING DATE

TC/A.U.

July 9, 2003

2627

(Use several sheets if necessary)

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/JH/	2004/0263185	12/2004	Cho et al.	324	636	
	2004/0114913	06/2004	Kume	386	125	
	2003/0053400	03/2003	Cho et al.	369	126	
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	2003/0021213	01/2003	Hagiwara, Yoshiaki	369	101	
	4,320,491	03/1982	Rustman, James C.	369	126	
	5,418,029	05/1995	Yamamoto et al.	428	64.2	
	5,481,527	01/1996	Kasanuki et al.	369	126	
	5,646,932	07/1997	Kuribayashi et al.	369	126	
	5,914,920	06/1999	Yokogawa	369	275.3	
	5,946,284	08/1999	Chung et al.	369	126	
	6,477,132	11/2002	Azuma et al.	369	126	
	6,510,130	01/2003	Hayashi et al.	369	275.3	
	6,515,957	02/2003	Newns et al.	369	126	
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	6,762,402	07/2004	Choi et al.	250	234	
	6,841,220	01/2005	Onoe et al.	428	66.7	
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	6,965,545	11/2005	Hino et al.	369	13.54	
	7,065,033	06/2006	Onoe et al.	369	126	
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DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
/JH/ 2003085969	03/2003	JP			ABSTRACT
/JH/ 08-075806	03/1996	JP			ABSTRACT
/JH/ 10-334525	12/1998	JP			ABSTRACT
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/JH/	62th Japan Society of Applied Physics Lecture Meeting (2001.9 Aichi Institute of Technology) 12p-ZR-2.
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\*Examiner

/Joseph Haley/

Date Considered

05/09/2007

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*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
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	2005/0122886	06/2005	Takahashi et al.	369	126	
	2005/0099895	05/2005	Maeda et al.	369	13.01	
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DOCUMENT			DATE	COUNTRY	CLASS	SUBCLASS	YES	NO
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/JH/	Kazuta et al, "Determination of crystal polarities of piezoelectric thin film using scanning nonlinear dielectric microscopy", Journal of European Ceramic Society 21 (2001) 1581-1584.
/JH/	The Institution of Electrical Engineers, Stevenage, GB; 1 June 2002; Hiranaga et al, "Nano-sized inverted domain formation in stoichiometric LiTaO <sub>3</sub> /single crystal using Scanning Nonlinear Dielectric Microscopy", XP002292217.
/JH/	Cho et al, "Scanning nonlinear dielectric microscopy with nanometer resolution", Journal of European Ceramic Society 21 (2001) 2131-2134.
/JH/	Cho et al., "Nano domain engineering using scanning nonlinear dielectric microscopy, October 29, 2001, IEE-NANO 2001, pages 352-357.

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